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PATENTS
CIPHBIO-011 CON

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Sidney E. Buttrill, Jr.
Application No.: 10/758,326 Confirmation No.: 6401
Filed : January 14, 2004
For : ELECTRIC SECTOR TIME-OF-FLIGHT MASS
SPECTROMETER WITH ADJUSTABLE ION
OPTICAL ELEMENTS
Group Art Unit : 2878

Mail Stop Amendment
Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

TRANSMITTAL LETTER FOR
INFORMATION DISCLOSURE STATEMENT

Sir:

Transmitted herewith is an Information Disclosure Statement in the above-identified application. This Statement is submitted:

- ☐ within three months of the application filing date;
- ☒ more than three months from the application filing date but before the mailing date of the first Office Action on the merits.

In accordance with 37 C.F.R. § 1.97, submission of this Statement requires no fee. However, if for any reason a fee is due, the Director is hereby authorized to charge payment of any fees required in connection with this

Information Disclosure Statement to Deposit Account
No. 06-1075. A duplicate copy of this letter is
transmitted herewith.

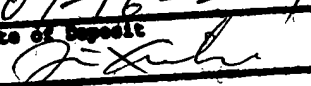
Respectfully submitted,

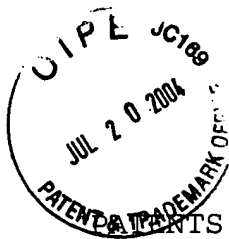


Tae Bum Shin
Limited recognition pursuant to
37 C.F.R. §10.9(b)
(Signed in a representative
capacity as Agent for Applicant
pursuant to 37 C.F.R. § 1.34(a))

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New York, New York 10020-1104
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VA 22313-1450 on:

07-16-2004
Date of Deposit

Lily Jiang
07-16-2004
Date of Signature



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Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98,
applicant hereby makes the following documents of record in
the above identified application:*

U.S. Patents

6,674,069	01/2004	Martin et al.
6,600,155	07/2003	Andrien et al.
6,300,625	10/2001	Ishihara
5,696,375	12/1997	Park et al.
5,665,967	09/1997	Coxon et al.
5,365,064	11/1994	Rettinghaus
5,357,107	10/1994	Ibach et al.
5,198,666	03/1993	Bateman
5,194,732	03/1993	Bateman
5,128,543	07/1992	Reed et al.

* Applicant reserves the right to challenge the status
of any of the cited documents as prior art.

5,097,125	03/1992	Gruen et al.
5,032,723	07/1991	Kono
4,973,842	11/1990	Gruen et al.
4,959,544	09/1990	Sukenobu
4,945,236	07/1990	Mogami et al.
4,889,987	12/1989	Gruen et al.
4,864,130	09/1989	Gruen et al.
4,855,596	08/1989	Gruen et al.
4,800,273	01/1989	Phillips
4,774,408	09/1988	Gohlke
4,754,135	06/1988	Jackson
4,472,631	09/1984	Enke et al.
4,234,791	11/1980	Enke et al.
3,986,025	10/1976	Fujiwara et al.
3,863,068	01/1975	Poschenrieder
3,745,343	07/1973	Halliday et al.
3,576,992	05/1971	Moorman et al.

Foreign Patents

2003-086129	03/2003	Japan
2000-243346	09/2000	Japan
2000-243345	09/2000	Japan
11-297267	10/1999	Japan
11-195398	07/1999	Japan
11-135061	05/1999	Japan
08-007831	01/1996	Japan
63-266751	11/1988	Japan

Other Documents

Matsuda, H., "High-resolution mass spectrometer," Shitsuryo Bunseki Vol. 33, No. 4, pp 227-234 (1985).

Matsuo, T., et al., "Ion optics of new TOF mass spectrometer in the order approximation," Nucl. Instrum. Methods Phys. Res. Sect. A, Vol. A256, No. 3, pp 327-330 (1987).

Nose, N., "High-resolution time-of-flight analyzer for charge exchange process," Shitsuryo Bunseki Vol. 31, No. 3, pp 165-172 (1983).

Sakurai et al., "Ion Optics for Time-of-Flight Mass Spectrometers with Multiple Symmetry," Int. J. Mass. Spectrom. Ion Proc. 63: pp 273-287 (1985).

Sakurai et al., "A New Time-of-Flight Mass Spectrometer," Int. J. Mass. Spectrom. Ion Proc. 66: pp 283-290 (1985).

Wollnik, Hermann, Optics of Charged Particles, Orlando: Academic Press, 1987, pp 201-205.

Wollnik, Hermann, Focusing of Charged Particles, Vol. 2, Albert Septier, ED, New York: Academic Press, 1967, pp 163-202 (Chapter 4.1).

In accordance with 37 C.F.R. § 1.98 (d), copies of these documents, all of which were made of record in U.S. Patent Application No.10/424,351, from which priority is claimed under 35 U.S.C. § 120, are not submitted herewith.

It is respectfully requested that these documents be (1) fully considered by the Patent and Trademark Office during the examination of this application; and (2) printed on any patent that may issue on this application. Applicant requests that a copy of Form PTO-1449, as considered and initialed by the Examiner, be returned with the next communication.

An early and favorable action is respectfully
requested.

Respectfully submitted,



Tae Bum Shin
Limited recognition pursuant to
37 C.F.R. §10.9(b)
(Signed in a representative
capacity as Agent for Applicant
pursuant to 37 C.F.R. § 1.34(a))

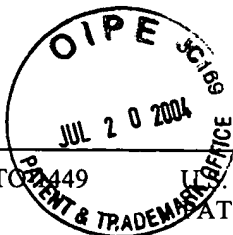
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[Signature]
Lily Jiang

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FORM PTO 449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. CiphBio-11 CON	SERIAL NO. 10/758,326
	APPLICANT Sidney E. Buttrill, Jr.	
	FILING DATE January 14, 2004	GROUP 2878

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,674,069	01/2004	Martin et al.			
	6,600,155	07/2003	Andrien et al.			
	6,300,625	10/2001	Ishihara			
	5,696,375	12/1997	Park et al.			
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	4,234,791	11/1980	Enke et al.			
	3,986,025	10/1976	Fujiwara et al.			
	3,863,068	01/1975	Poschenrieder			
	3,745,343	07/1973	Halliday et al.			
	3,576,992	05/1971	Moorman et al.			

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. CiphBio-11 CON	SERIAL NO. 10/758,326
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FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	2003-086129	03/2003	Japan			Abstract	
	2000-243346	09/2000	Japan			Abstract	
	2000-243345	09/2000	Japan			Abstract	
	11-297267	10/1999	Japan			Abstract	
	11-195398	07/1999	Japan			Abstract	
	11-135061	05/1999	Japan			Abstract	
	08-007831	01/1996	Japan			Abstract	
	63-266751	11/1988	Japan			Abstract	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIALS	
	Matsuda, H., "High-resolution mass spectrometer," Shitsuryo Bunseki Vol. 33, No. 4, pp 227-234 (1985).
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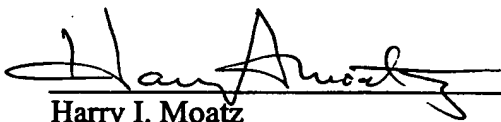
**BEFORE THE OFFICE OF ENROLLMENT AND DISCIPLINE
UNITED STATE PATENT AND TRADEMARK OFFICE**

LIMITED RECOGNITION UNDER 37 CFR § 10.9(b)

Mr. Tae Bum Shin is hereby given limited recognition under 37 CFR §10.9(b) as an employee of Fish & Neave to prepare and prosecute patent applications wherein the patent applicant is the client of Fish & Neave, and the attorney or agent of record in the applications is a registered practitioner who is a member of Fish & Neave. This limited recognition shall expire on the date appearing below, or when whichever of the following events first occurs prior to the date appearing below: (i) Mr. Tae Bum Shin ceases to lawfully reside in the United States, (ii) Mr. Tae Bum Shin's employment with Fish & Neave ceases or is terminated, or (iii) Mr. Tae Bum Shin ceases to remain or reside in the United States on an H-1B visa.

This document constitutes proof of such recognition. The original of this document is on file in the Office of Enrollment and Discipline of the U.S. Patent and Trademark Office.

Expires: December 14, 2004



Harry I. Moatz
Director of Enrollment and Discipline